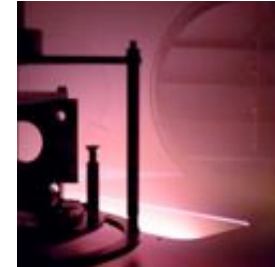
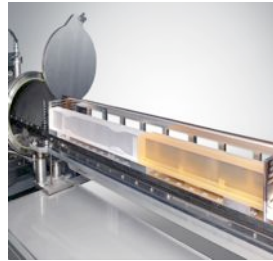


2nd workshop on X-ray and XUV active optics

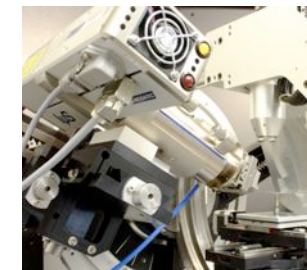
State-of-the-art thin film X-ray optics for synchrotrons and FEL sources

Frank Hertlein – Incoatec GmbH – Geesthacht, Germany

Incoatec: Innovative Coating Technologies



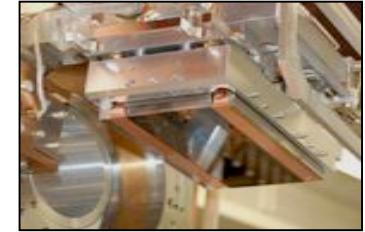
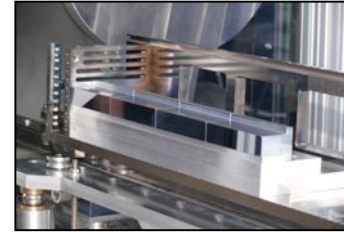
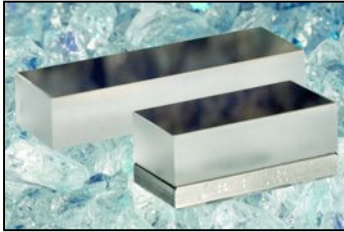
- Incoatec is founded with Bruker AXS in 2002
- Own R&D activities and application lab
- over 12 years of experience in X-ray optics and over 18 years of experience in thin film technology



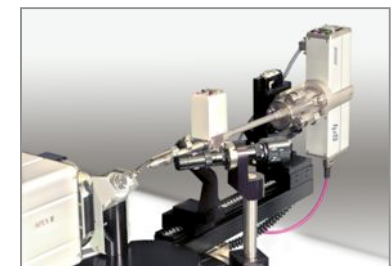
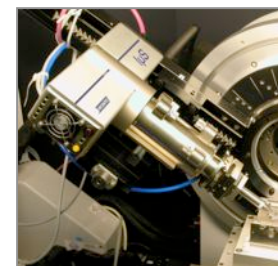
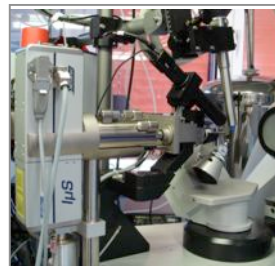
Outline

- Products & Services
- Multilayer coating
- Deposition of thin films
- Characterization
- Applications
 - Total reflection optic for FEL
 - Multi-stripe optic for Tomography Beamline
- Conclusion

Products & Services



- Multilayer mirrors
- Customized coatings for synchrotron mirrors and other applications



- Incoatec Microfocus Source $I\mu S^{\text{TM}}$
- Upgrades of existing equipment

Products: Incoatec Microfocus Source – $1\mu\text{S}$

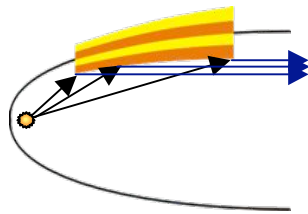
- High brilliance low-power microfocus source
- For Cu or Mo
- Air-cooled
- New type of 2D beam shaping Montel Optics:
The Quazar™ Optics
- New easy-to-align housing, optional with motors
- Low maintenance
- Tube change as easy as for conventional sealed-tubes
- 3 Years warranty



High performance at only 30 W

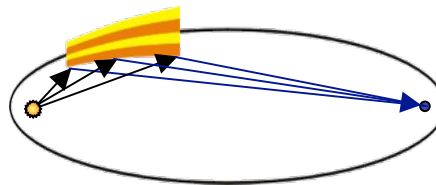
Products: Multilayer Mirrors

XRD



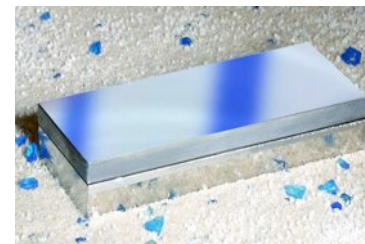
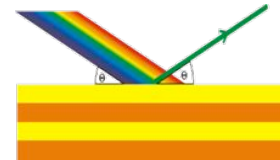
Göbel Mirror

SCD



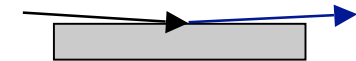
Montel Mirror

XRF



XRF - Multilayer
Analysator

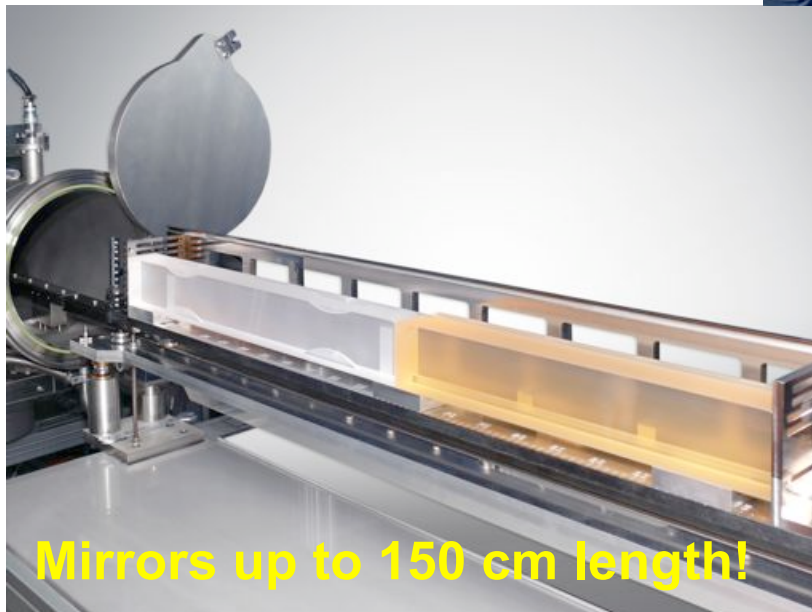
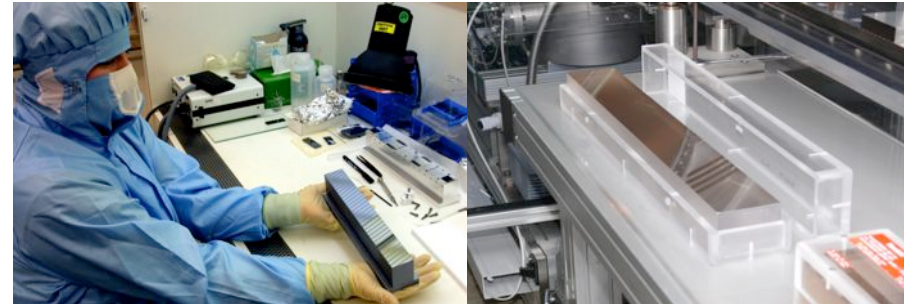
Synchro
-tron



Coating of
Synchrotron
Mirror
up to 150 cm

Products: X-ray Optics for Synchrotron Beamlines

Typical mirror substrate materials:
Fused Silica, Zerodur, Silicon, ...



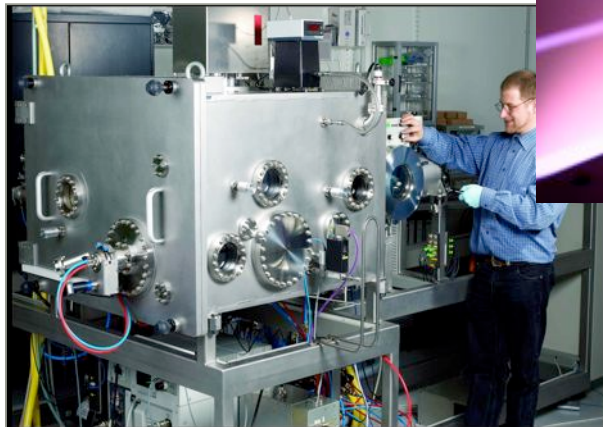
- **Special Carbon Coatings:** for High Flux Beamlines like FEL at DESY
- **Multilayer (Stripes) Coatings:** optimized for the most different applications, dimensions and shapes
- **Cooperation with GKSS:** R&D for film and deposition technology

We produce the coating for your optic as you like!

Deposition by Magnetron Sputtering



Argon Plasma



Optimized deposition facilities
for different sizes, gradients and precisions

Deposition of Thin Films

Magnetron Sputtering

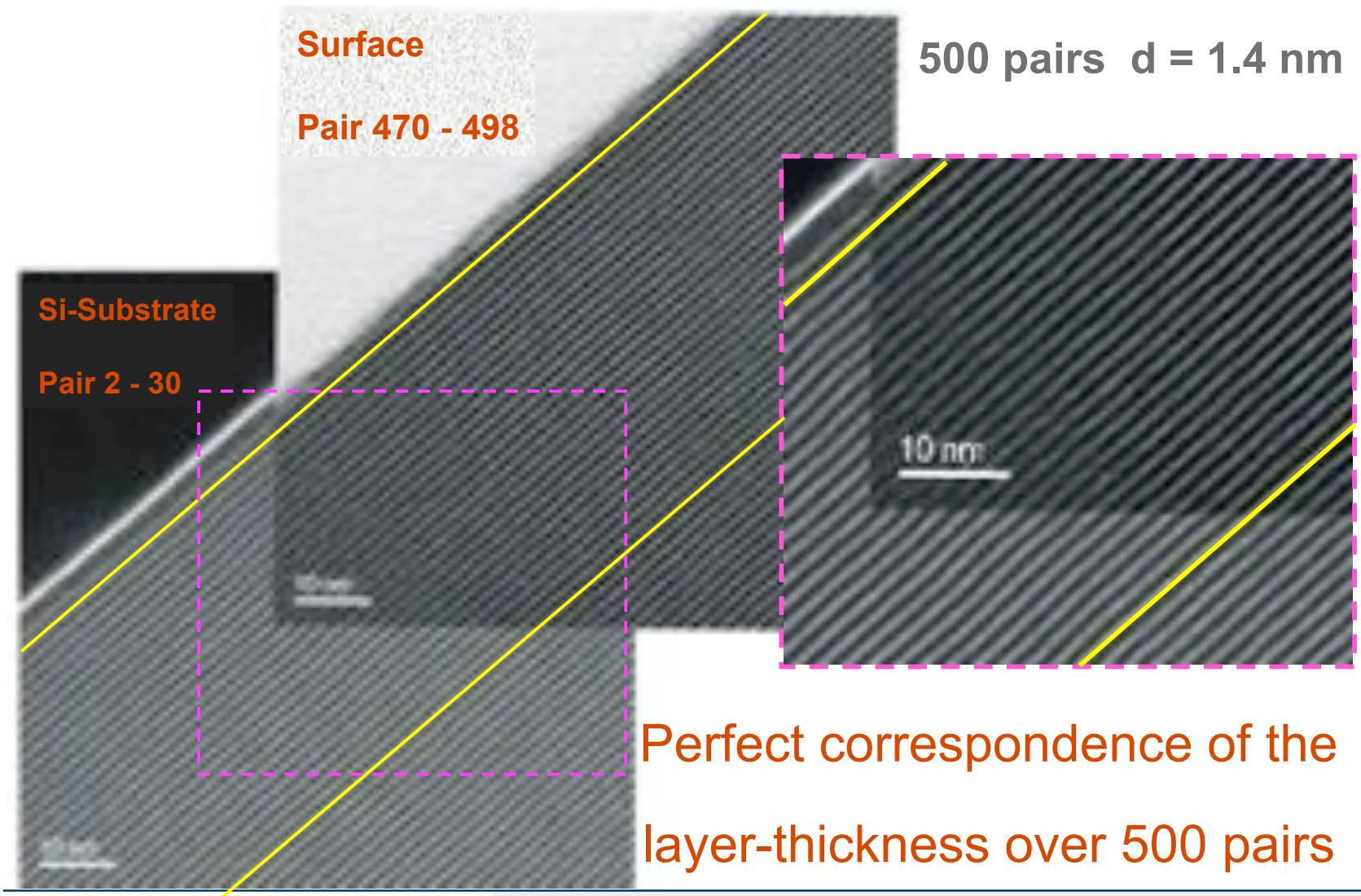
- **Monolayer, Multilayer, Graded-Multilayer, Stripe-Multilayer**
- **area for deposition:**
 - up to 150 x 12 x 12 cm
 - or 6" diameter
- **film thickness:** single layer 1..500 nm
- **Precision:** typical $\pm 1\%$, up to $\pm 0.1\%$



Requirement for coating

- **good homogeneity over the whole mirror, up to 0.2%**
- **exact d-spacing over the whole stack, with up to several hundred pairs**
- **low roughness, better than 0.3 nm**
- **sharp interfaces, none interdiffusion**

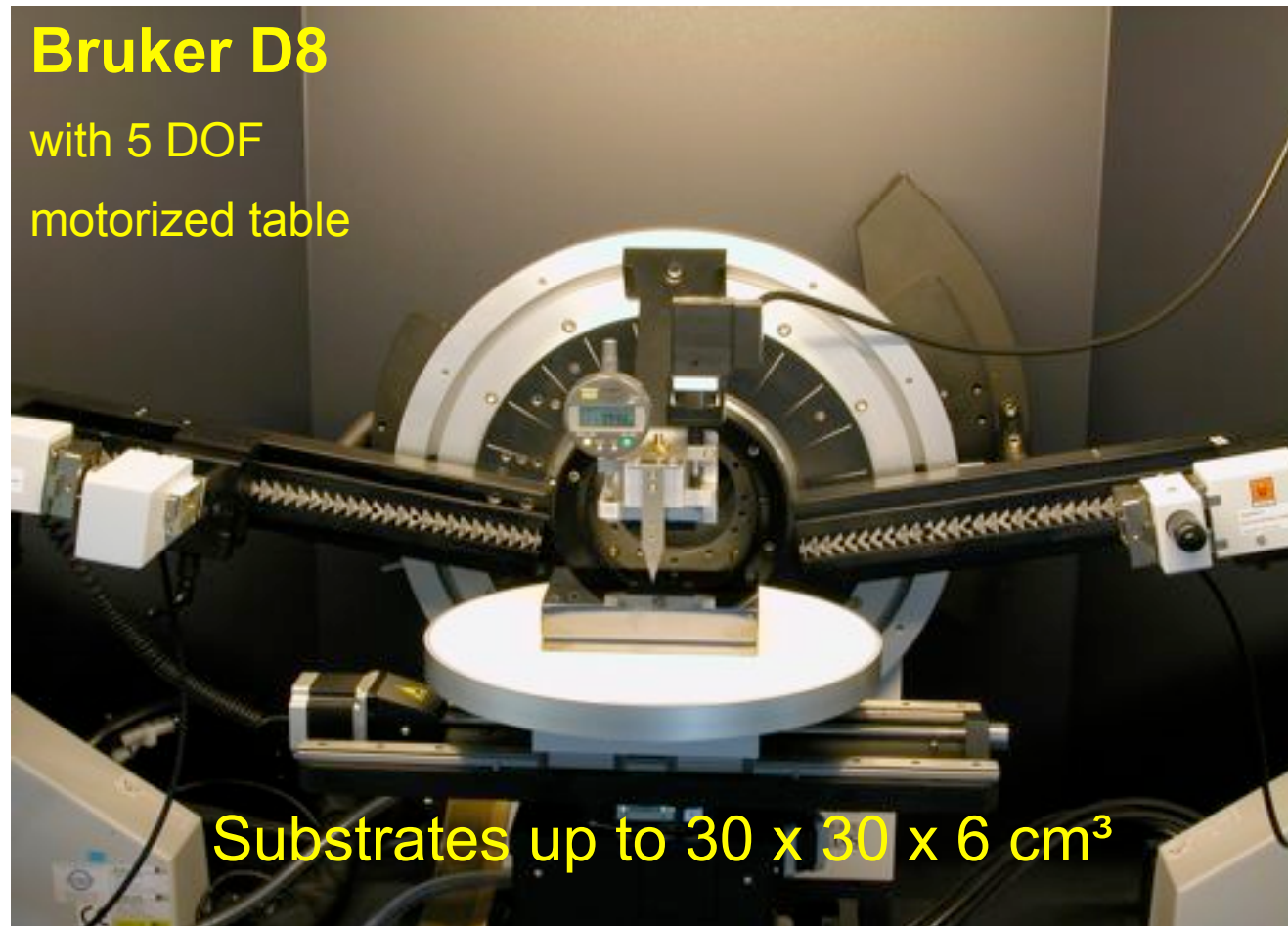
TEM-Picture of a multilayer coating



Characterization with XRR

Bruker D8

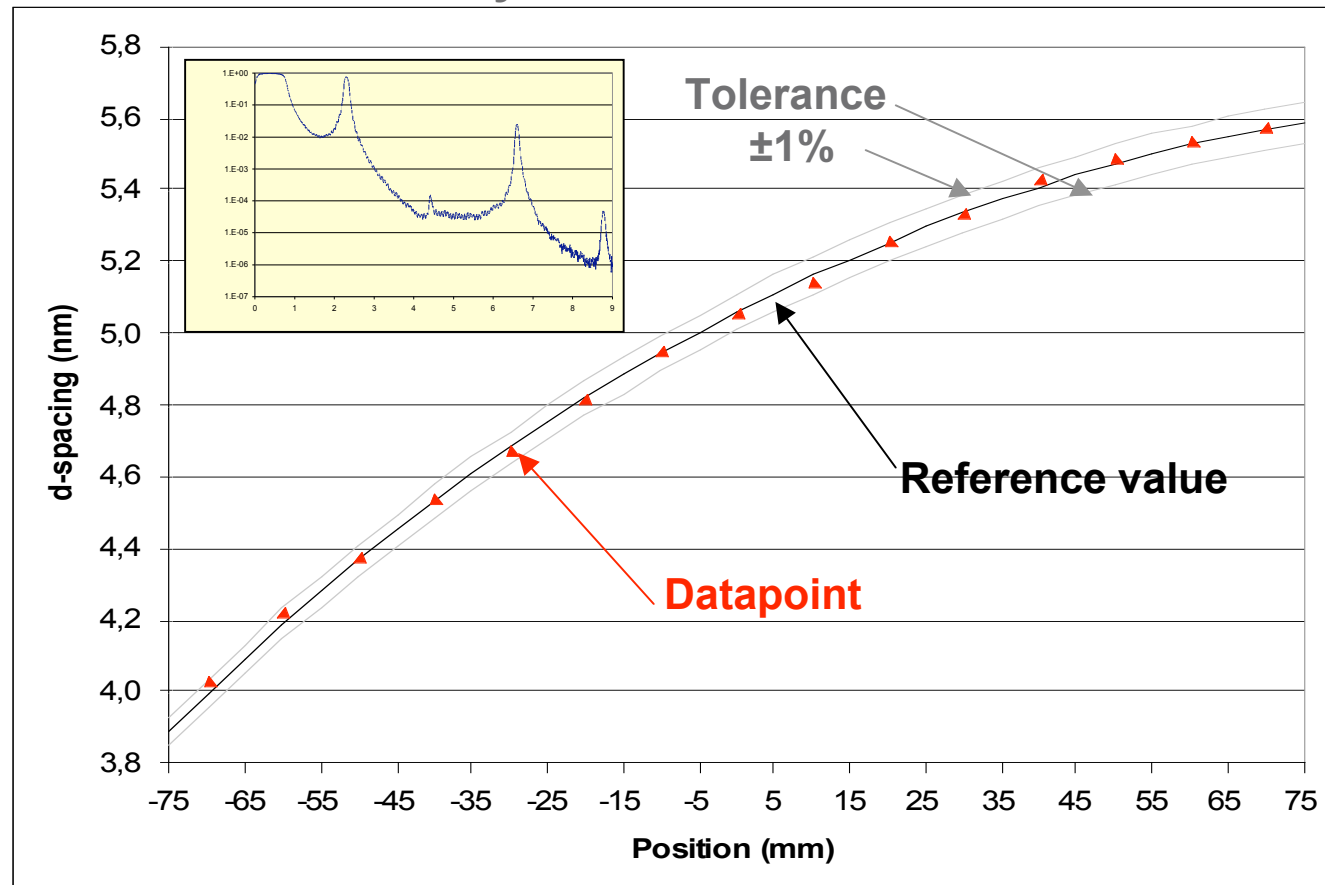
with 5 DOF
motorized table



Substrates up to 30 x 30 x 6 cm³

Characterization with XRR

Graded Multilayer Characterization with XRR



d-spacing accuracy better 1% !

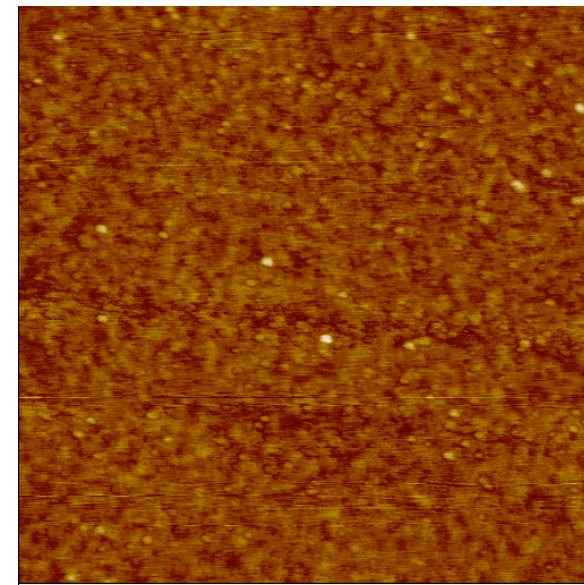
Characterization with SFM / AFM

Research & Development:

SFM
Scanning Force Microscope

AFM
Atomic Force Microscope

C-Film (38 nm) on Silicon



Scanning Force Microscopy
(F. Felten, TUHH)

0 1.00 μm
Data type Height
Z range 5.00 nm

$Rq, rms = 0.24 \pm 0.02 \text{ nm}$

Application I: Total reflection optics of carbon for FEL

Optics for FEL at Desy



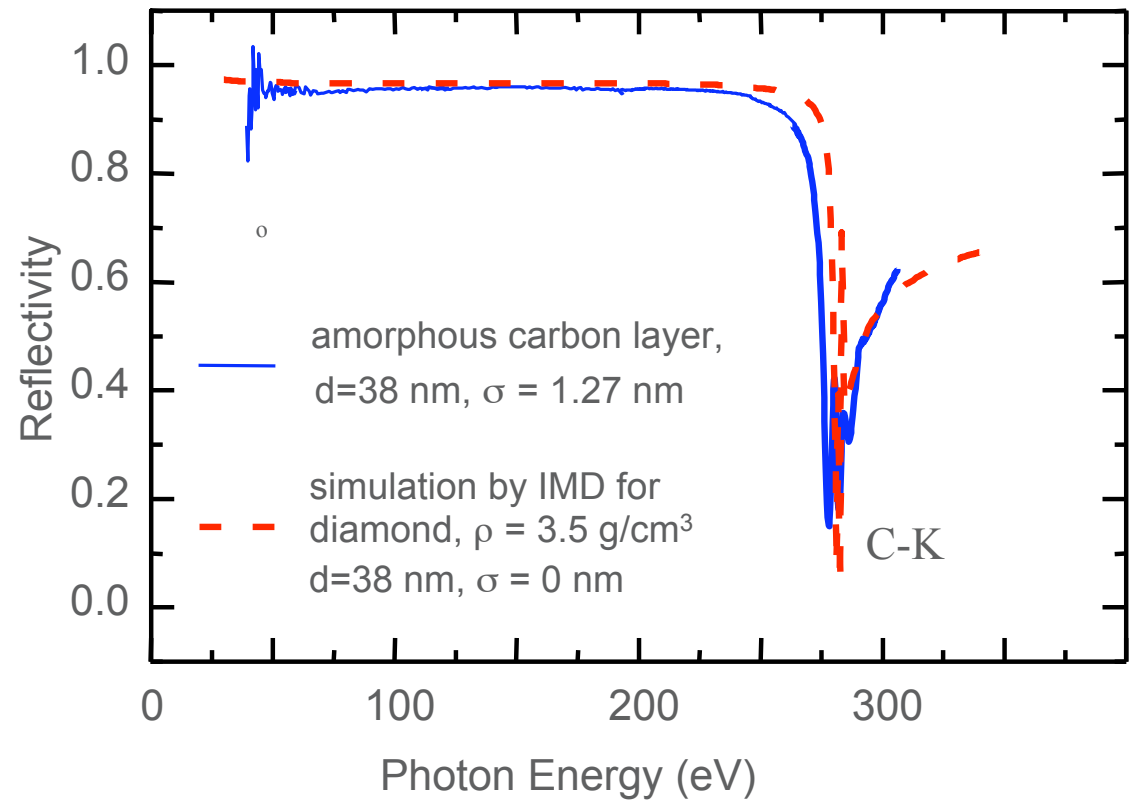
Substrate made by:



Coating made by:



Reflectivity vs. Energy measured by B. Steeg, Hasylab



$R(E) \sim 95-96\%$ at 50 - 250 eV at grazing incidence of 2 deg

Characterization of Total Reflection Optics

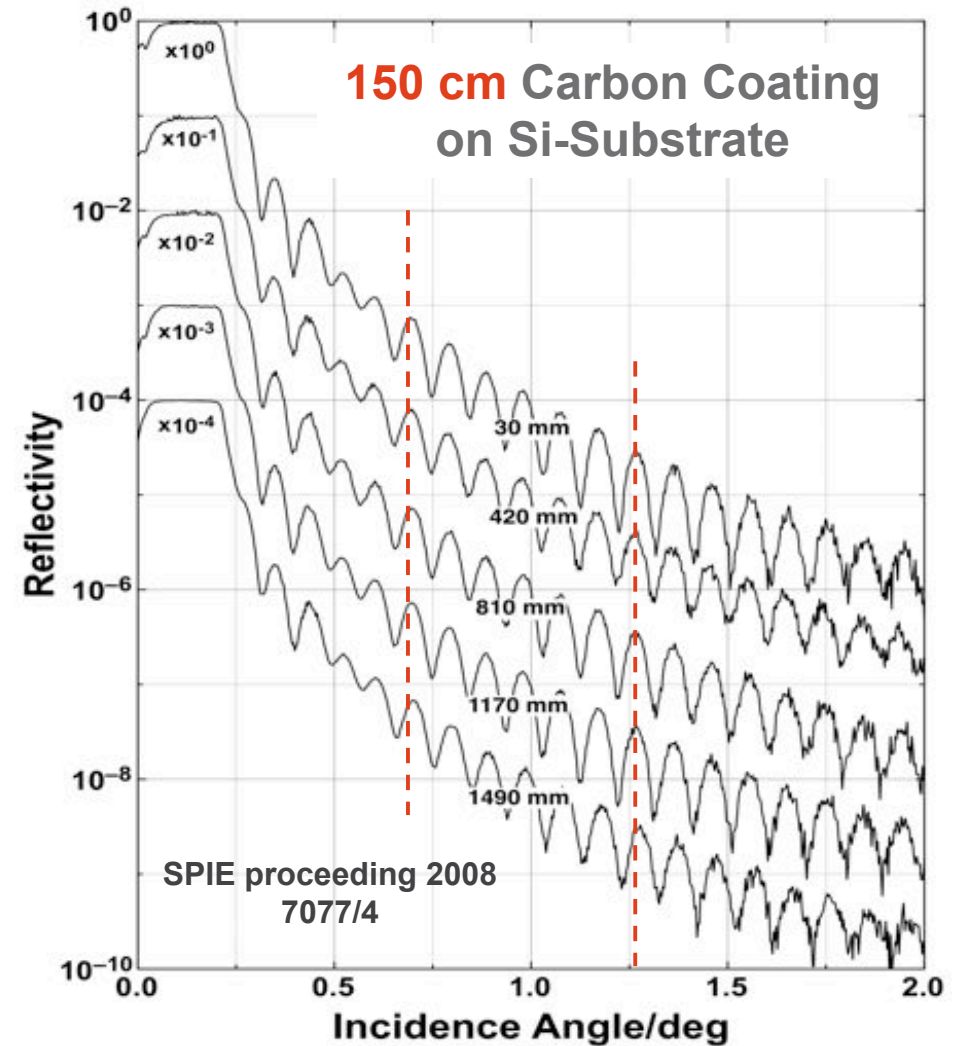
XRR measurement with
Cu-K α (8 keV) at different positions

density: 2.2 g/cm 3

roughness: 0.5 nm

thickness: 44.2 nm

Measured by M. Störmer, GKSS



Characterization of Total Reflection Optics

Mean film thickness

44.2 nm

Standard deviation

0.2 nm rms

Peak-to-Valley

~1 nm

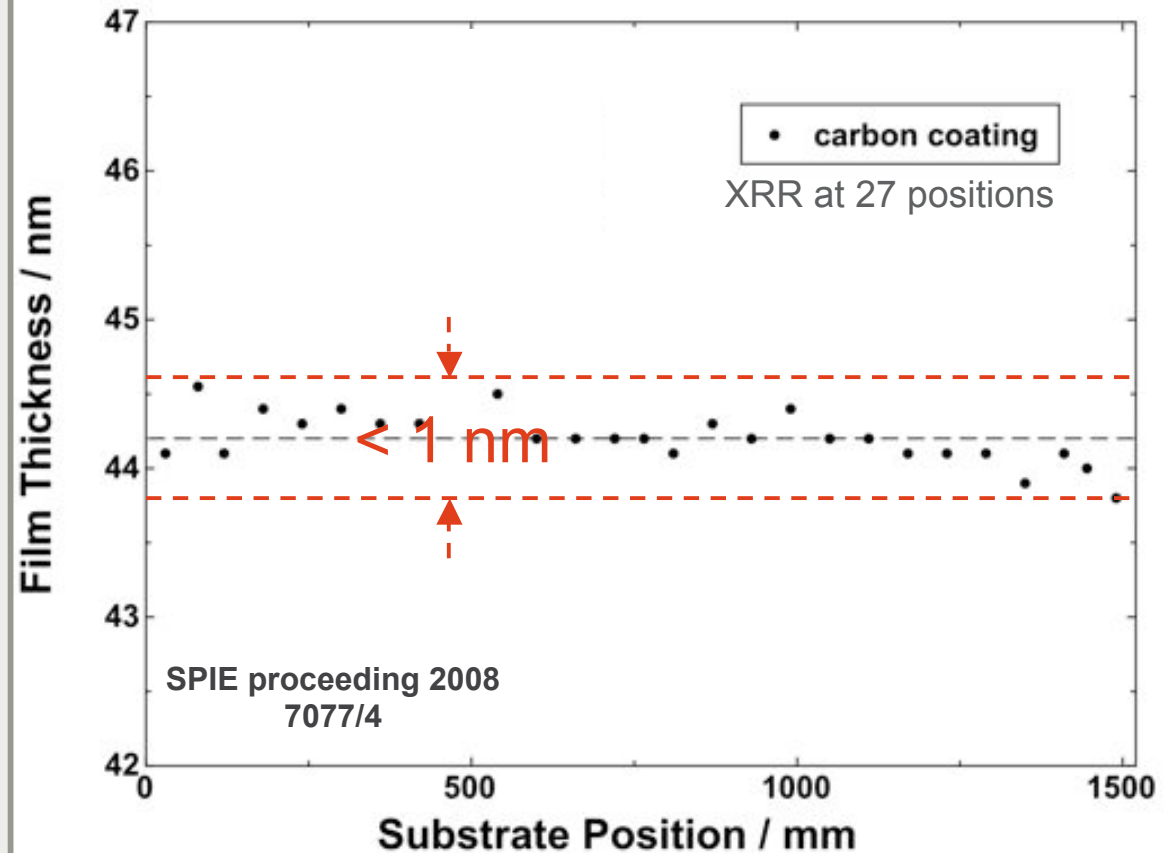
Homogeneity

better 2 %

Measured by M. Störmer,



150 cm Carbon Coating on Si-Substrate



Application II: Multi-stripe X-ray Optics

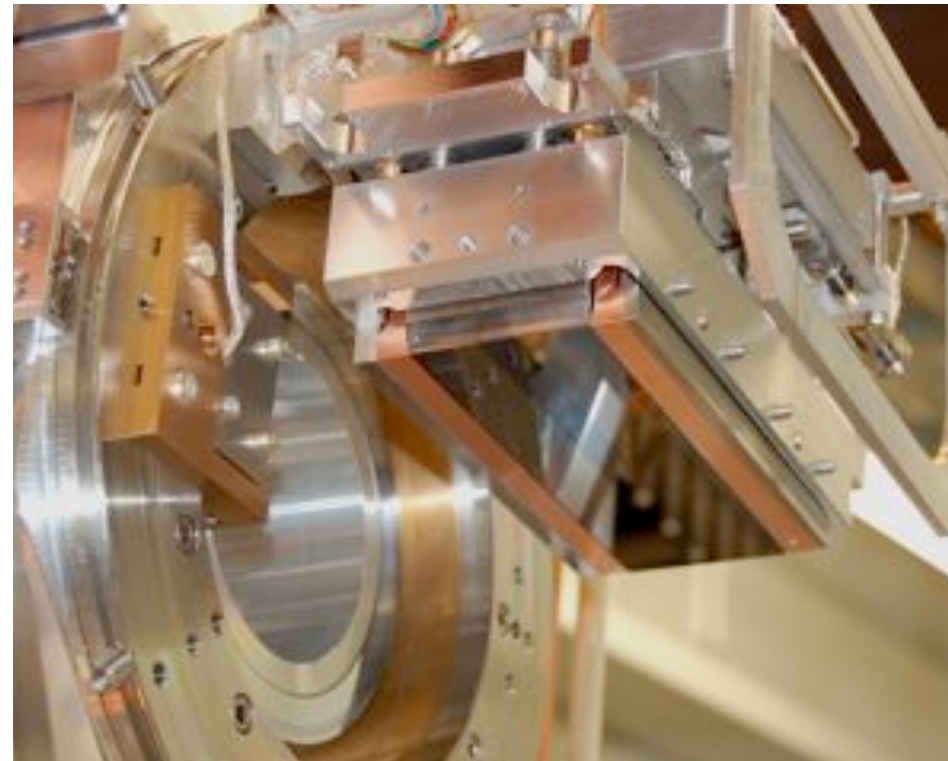
Tomography Beamline
(M. Stampanoni, PSI-SLS)



Substrate made by:



Coating made by:



Picture courtesy of M. Stampanoni, PSI-SLS

Stripe A : [Ru/C]₁₀₀, $d = 40 \text{ \AA}$, $\gamma = 0.5$, $R > 80\%$ for $10 < E < 22 \text{ keV}$

Midspace: Si111, $D_{\text{orientation}} < 0.01^\circ$, $\sigma = 0.1 \text{ nm}$, slope error $0.04''$

Stripe B : [W/Si]₁₀₀, $d = 30 \text{ \AA}$, $\gamma = 0.5$, $R > 80\%$ for $22 < E < 45 \text{ keV}$

Conclusion - Our profile

- Simulation of layer and optics properties
 - Flexible, on customer request
- Physical Vapour Deposition (PVD) methods for coatings
 - extreme precise coatings
 - large area coatings
 - with gradients / stripes / monolayer / multilayer
- Characterization of thin films

We produce the optics as you like!

Flexible “in-house” manufacturing for various wavelengths and applications

Conclusion - Our costumers

- Zeiss



- JenOptik



- Desy / Hasylab



- Bessy



- University of Hamburg



- University Göttingen



- APS / ANL



- Swiss Light Source
PSI



- SESO



- ...

Thank you for your attention

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